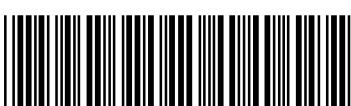


<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	110723664	BURKE ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	RICHARD CHAN	2618

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
455	574, 552.1, 550.1, 572, 343.1	8/1/08	RC

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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